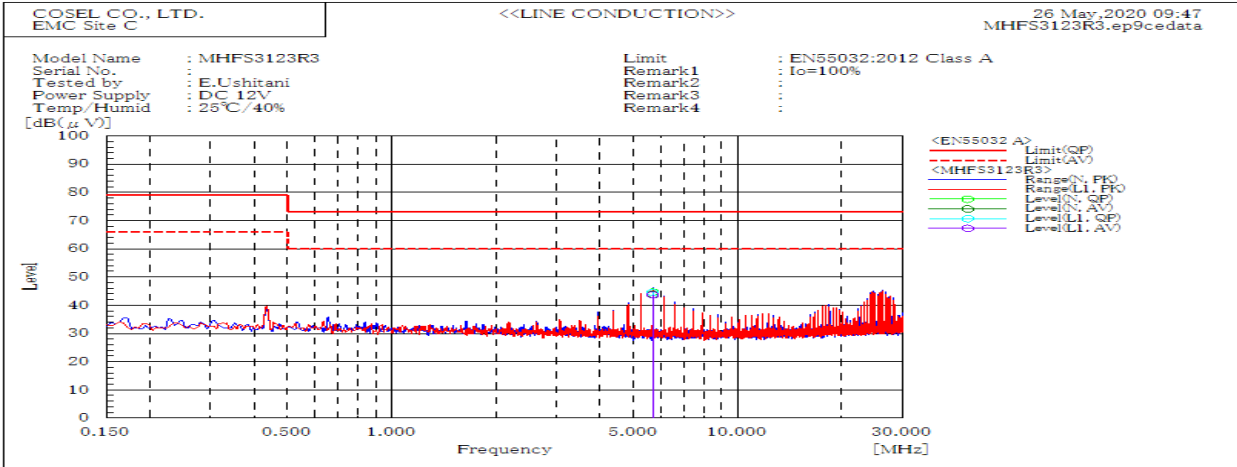
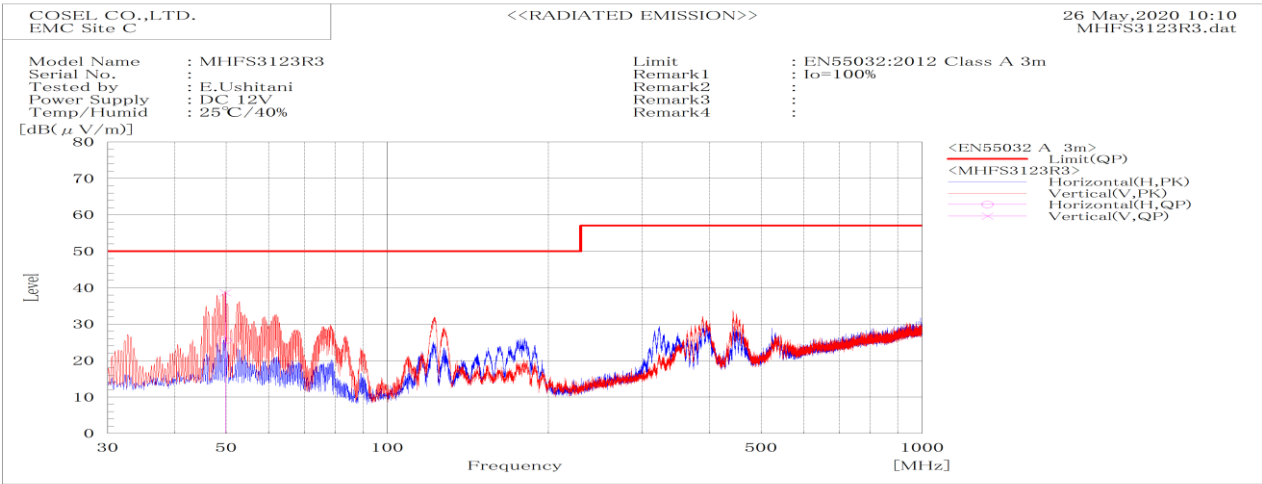


DATA SHEET		Date	04-Jun-20
Model	MHFS3123R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



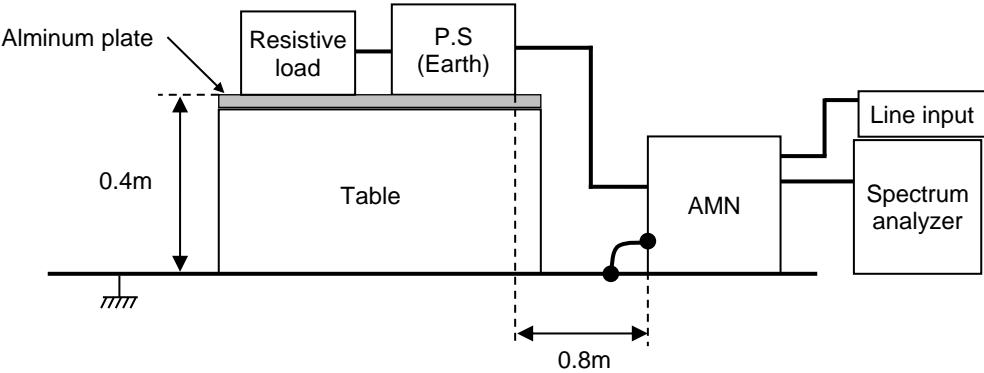
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
5.672	L1	44.6	43.7	73	60	28.4	16.3	Pass	
5.673	N	44.7	43.9	73	60	28.3	16.1	Pass	



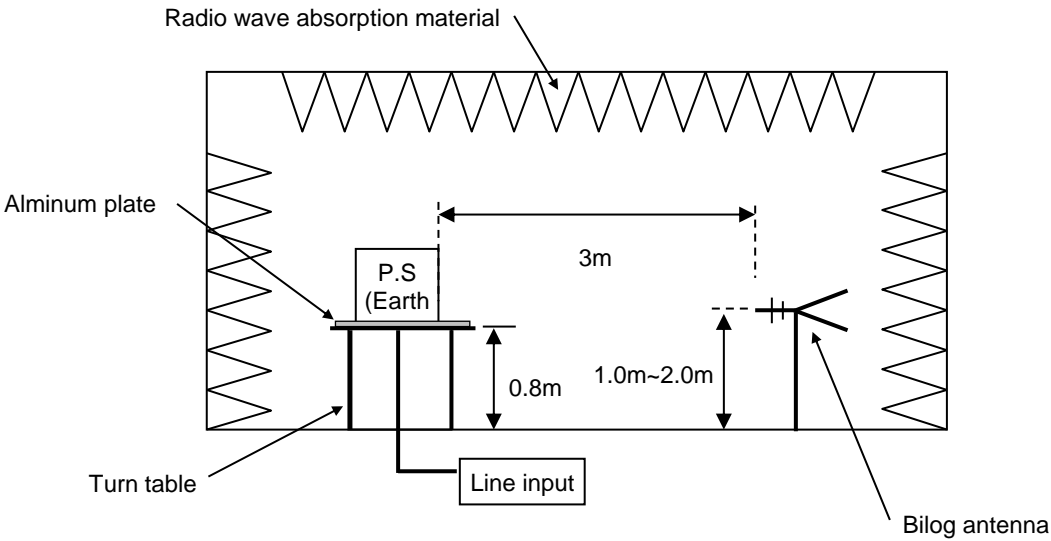
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
49.78	H	Stable	25.5	50	24.5	Pass	100	0	
49.78	V	Stable	38.6	50	11.4	Pass	100	0	

DATA SHEET		Date	04-Jun-20
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission



Conditions

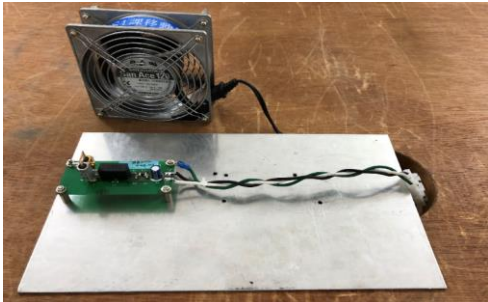
Test : EMI
Model Name: MHFS3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

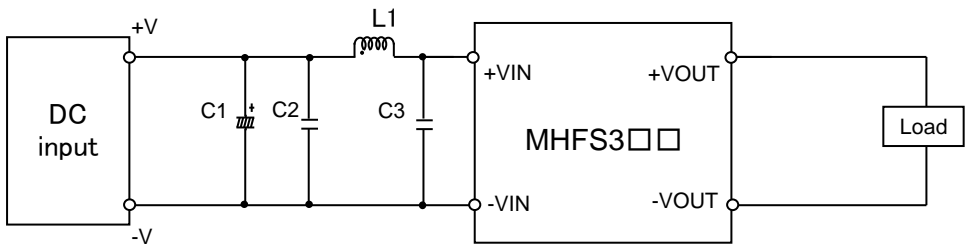


Fig.1 Testing circuitry

C1 :	MHFS312□□	50V 100μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS324□□	-
	MHFS348□□	-
C2 :	MHFS312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS312□□	1200mA 4.7μ H Inductor(LQH32PN4R7NNCL MURATA MANUFACTURING)
	MHFS324□□	900mA 10μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING)
	MHFS348□□	550mA 22μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING)